Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/531,245	SENKEVICH ET AL.	
Examiner	Art Unit	
SEYED MASOUD	1722	

SEARCHED					
Class	Subclass	Date	Examiner		
117	84	2/1/2007	SMM		
117	88	2/1/2007	SMM		
117	89	2/1/2007	SMM		
117	99	2/1/2007	SMM		
117	102	2/2/2007	SMM		
117	104	2/2/2007	SMM		
117	105	2/2/2007	SMM		
27					
	١				
	,				
		,			

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
<u> </u>					

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
Use Palm Intranet to search inventor's name	2/1/2007	SMM
Use text search through East to find prior art. Examiner used key words such as " Atomic Layer Deposition"	2/1/2007	SMM
	1.0	
	-	